

Supporting Information

Controlled fabrication of osmium nanocrystals by electron, laser and microwave irradiation and characterisation by microfocus X-ray absorption spectroscopy

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Materials and methods

Materials. The preparations of the complexes [Os(η^6 -*p*-cym)(1,2-dicarba-*closo*-dodecarborane-1,2-dithiolato)] (**1**), [Os(η^6 -*p*-cym)(1,2-dicarba-*closo*-dodecarborane-1,2-dithiolato)(triphenylphosphine)] (**2**), and **OsMs** were based on previous reports.^{1, 2} The triblock copolymer P123 [poly(ethylene glycol)-*block*-poly(propylene glycol)-*block*-poly(ethylene glycol)] was purchased from Sigma-Aldrich. Anhydrous tetrahydrofuran (Aldrich) was used. 18.2 M Ω ·cm purity water was collected from a Purelab[®] UHQ USF Elga system. Holey carbon grids with 200 gold mesh and lacey carbon grids were purchased from Quantifoil Micro Tools GmbH and Elektron Technology UK Ltd, respectively.

TEM imaging: TEM data were obtained on a JEOL 2000FX electron microscope at an acceleration voltage of 200 kV. High magnification TEM images were obtained on a JEOL 2100FX electron microscope at an acceleration voltage of 200 kV. TEM samples were prepared on lacey (holey) carbon on 200 mesh gold grids. A drop of sample (5 μ L, 1 mg/mL) was deposited on the grid and left to air-dry.

Laser irradiation: A drop of an aqueous solution of **OsMs** (5 μ L, 1 mg/mL) was deposited on lacey carbon 400 mesh gold TEM grids (**G2**) as described above. The grids were then irradiated for 5 h using a 1 kHz pulsed laser beam with a pulse duration of 40 femtoseconds (10^{-15} s), generated by a commercially available Ti:sapphire regenerative amplifier (Newport Spectra-Physics Spitfire Pro) seeded by a Ti:sapphire oscillator (Newport Spectra-Physics Tsunami). The wavelength of the laser was centred at 800 nm with a bandwidth of 30 nm (full width half maximum) with an average power of 33 mW to produce Os nanocrystals.

Microwave irradiation: 100 mg of freeze-dried **OsMs** were heated at 190 °C for 8 min at 250 psi in a sealed vessel, using a Biotage Initiator 2.0 microwave synthesizer (400 W). The residue was dissolved in water, and a drop of sample (5 μ L, 1 mg/mL) was deposited on a TEM grid and left to air-dry for examination by high-resolution TEM (**G3**).

Microfocus XAFS: All the XAS data were obtained on beamline I18³f Diamond Light Source using a Si (111) monochromator. A 5 \times 5 micron beam was used for the microXAS data collection in fluorescence mode, while the beam size was increased to 50 \times 50 microns to collect the transmission EXAFS data. Fluorescence data were obtained using a 9 element Ortec Ge detector. XAS data were analysed using the Demeter suite of programs Athena and Artemis using multiple scattering paths in the carbon ring for complex **2**.⁴ Note that for complex **2** the EXAFS signal is dominated by the S/P shell so the thermal parameters are large for the carbon shells.

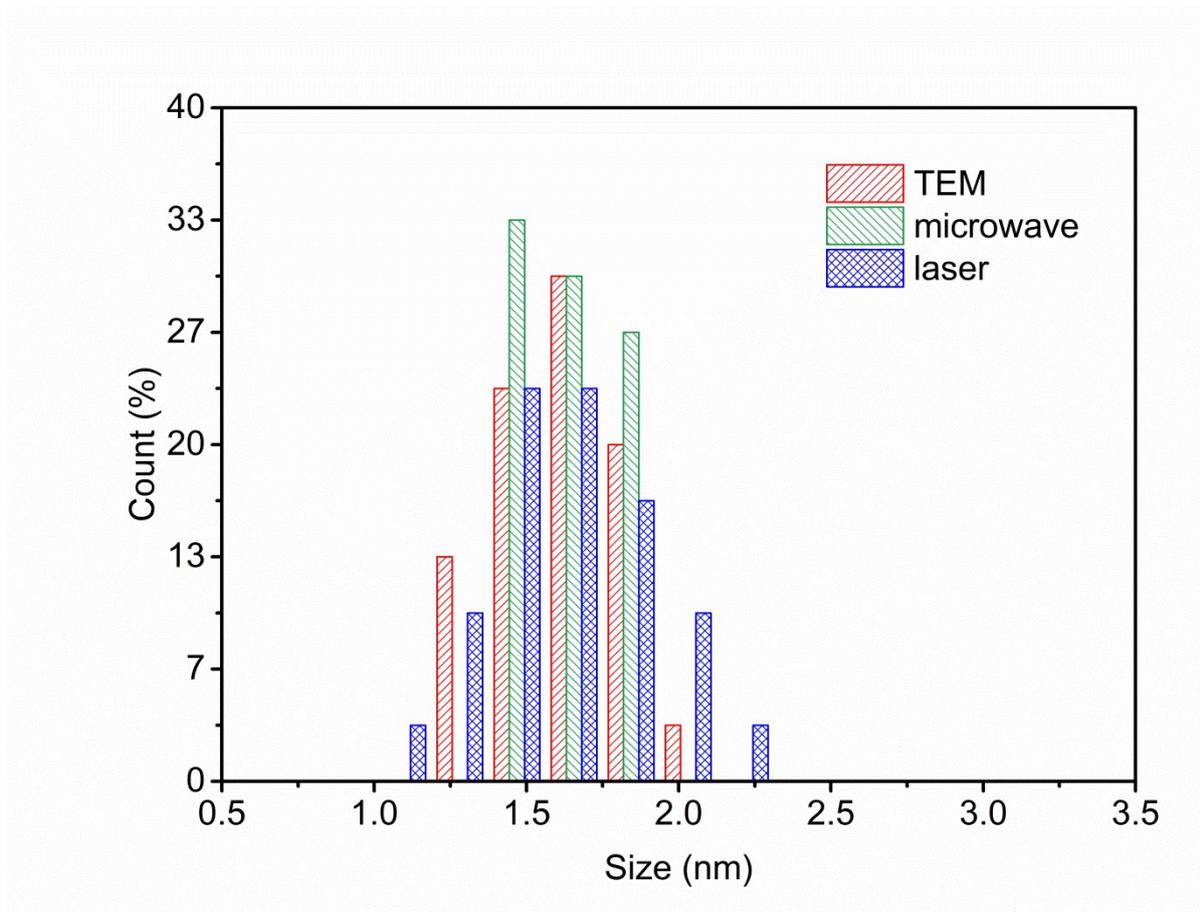


Fig. S1. Size distribution of the nanocrystals produced *via* electron-, microwave-, and laser-irradiation methodologies.

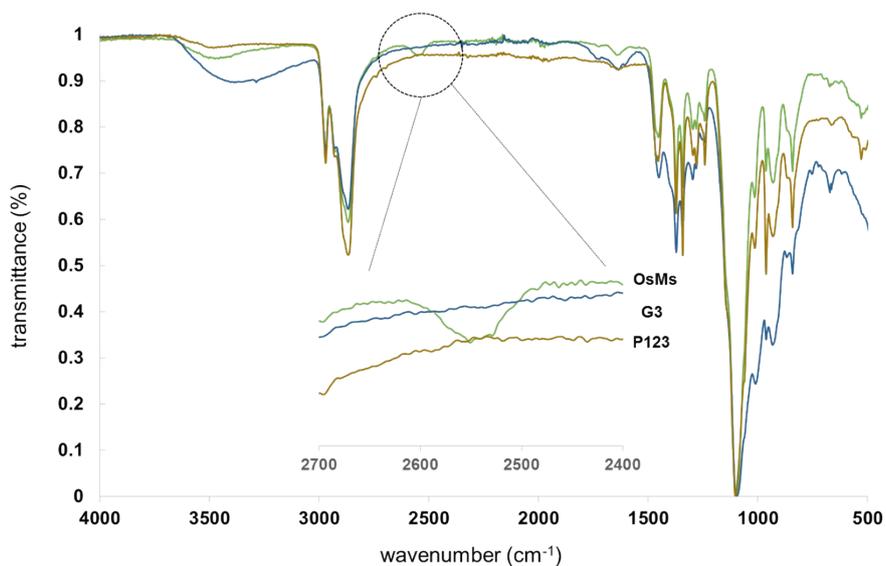


Fig. S2 Infrared spectra of Pluronic P123 (brown), **OsMs** (green) and **OsMs (G3)** after microwave irradiation (blue). Inset shows the disappearance of the characteristic carborane B–H stretching vibration band at 2550 cm⁻¹ after microwave treatment.

Table S1 XANES analysis of grids. Each region is the average of 4-6 scans.

Sample	Region	White Line Energy / eV	Os Oxidation State
Electron-beam irradiation G1	1 (EXAFS)	10877.150	1.30
	2	10877.002	1.00
	3	10877.001	1.00
	4	10877.667	2.34
	5	10877.997	2.99
	6	10877.833	2.67
	Mean	10877.442	1.88
Laser irradiation G2	1 (EXAFS)	10876.900	0.80
	2	10877.563	2.13
	3	10877.166	1.33
	4	10877.274	1.55
	Mean	10877.226	1.45
Microwave irradiation G3	1 (EXAFS)	10876.650	0.30
	2	10877.332	1.66
	3	10876.837	0.67
	4	10877.249	1.50
	5	10876.461	-0.08
	Mean	10876.906	0.81

Table S2 Fitted EXAFS parameters. S_0^2 is the amplitude reduction factor and E_0 the threshold energy. R_{cryst} is the crystallographic interatomic distance (from the structures indicated in the footnotes) and R_{fitted} the refined interatomic distance. σ^2 is the Debye Waller factor.

Sample	Shell	N	$R_{\text{cryst}} / \text{\AA}$	$R_{\text{fitted}} / \text{\AA}$	$\sigma^2 / \text{\AA}^2$
18 e complex 2 [Os(η^6 - <i>p</i> -cym)(1,2-dicarba- <i>closo</i> -dodecarborane-1,2-dithiolate)(triphenylphosphine)] ¹ $S_0^2 = 0.83$ (fixed) $E_0 = 14.0$ eV	C	6	2.255	2.24(2)	0.021(7)
	S (P)	3	2.392	2.40(4)	0.004 (3)
	C	2	3.349	3.37(2)	0.016(16)
16 e complex 1 [Os(<i>p</i> -cymene)(1,2-dicarba- <i>closo</i> -dodecarborane-1,2-dithiolate)] ² $S_0^2 = 0.81(20)$ $E_0 = -1.543 \pm 3.11$ eV	Os	12	2.675	2.660(16)	0.008(2)
	Os	6	3.825	3.76(4)	0.011(4)
Electron Beam irradiated grid 16 hours ³ G1 $S_0^2 = 1.211 \pm 1.04$ $E_0 = 2.1 \pm 7.4$ eV	Os	11	2.675	2.72(8)	0.022(13)
	Os	5.5	3.825	3.90(8)	0.012(10)
	S	2	2.266	2.33(4)	0.006(7)
Laser irradiated grid 5 hours ² G2	Os	12	2.675	2.61(8)	0.010(10)

$S_0^2 = 0.83(96)$ $E_0 = -8.507 \pm 13.26 \text{ eV}$	Os	6	3.825	3.64(10)	0.002(10)
Microwave solution grid ² G3 $S_0^2 = 1.01 \pm 0.82$ $E_0 = -12.0 \pm 11.5 \text{ eV}$	Os	12	2.675	2.61(6)	0.011(7)
	Os	6	3.825	3.70(10)	0.011(10)

1. Data fitted to crystal structure of ruthenium analogue CSD-QENJUO Herberhold et al.⁵
2. Data fitted to crystal structure of osmium metal published by Swanson and Ugrinic⁶
3. Data fitted to crystal structure of osmium metal published by Swanson and Ugrinic⁶ with additional bond sulfur shell

References

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